









SN74HCS240

JAJSN34A - JULY 2021 - REVISED OCTOBER 2021

SN74HCS240 シュミット・トリガ入力と 3 ステート出力を備えたオクタル反 転ライン・ドライバ

1 特長

- 広い動作電圧範囲:2V~6V
- シュミット・トリガ入力により低速またはノイズの多い入力 信号に対応
- 低消費電力
 - I_{CC}: 100nA (標準値)
 - 入力リーク電流:±100nA (標準値)
- 6V で ±7.8mA の出力駆動能力
- 広い周囲温度範囲:-40℃~+125℃、Tム

2 アプリケーション

- ・ デジタル信号の有効化 / 無効化
- 遅い入力信号またはノイズの多い入力信号のノイズの 除去
- コントローラ・リセット時の信号保持
- スイッチのデバウンス

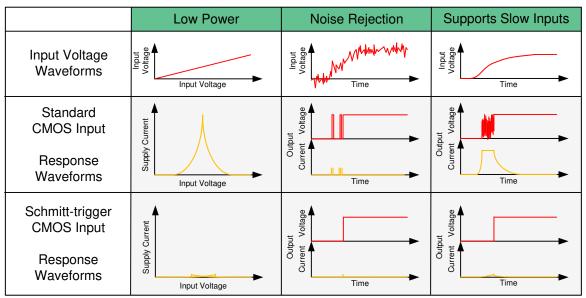
3 概要

このデバイスは、3 ステート出力とシュミット・トリガ入力を備えた 8 つの独立した反転ライン・ドライバで構成されています。各チャネルはブール関数 Y = Ā を正論理で実行します。チャネルは 4 つ 1 組に分けられ、各組を 1 本の OE ピンで制御できます。対応する OE ピンに HIGH を印加することで、出力をハイ・インピーダンス状態にできます。

製品情報

部品番号	パッケージ ⁽¹⁾	本体サイズ (公称)		
SN74HCS240RKS	VQFN (20)	4.50mm × 2.50mm		

(1) 利用可能なすべてのパッケージについては、このデータシートの 末尾にある注文情報を参照してください。



Benefits of Schmitt-trigger inputs



Table of Contents

1 特長 1	8.3 Feature Description
2 アプリケーション1	8.4 Device Functional Modes10
3 概要1	9 Application and Implementation1
4 Revision History	9.1 Application Information1
5 Pin Configuration and Functions	9.2 Typical Application11
6 Specifications4	10 Power Supply Recommendations14
6.1 Absolute Maximum Ratings4	11 Layout14
6.2 ESD Ratings 4	11.1 Layout Guidelines14
6.3 Recommended Operating Conditions4	11.2 Layout Example14
6.4 Thermal Information4	12 Device and Documentation Support15
6.5 Electrical Characteristics5	12.1 Documentation Support15
6.6 Switching Characteristics5	12.2 Receiving Notification of Documentation Updates 15
6.7 Operating Characteristics	12.3 サポート・リソース15
6.8 Typical Characteristics	12.4 Trademarks15
7 Parameter Measurement Information8	12.5 Electrostatic Discharge Caution15
8 Detailed Description9	12.6 Glossary15
8.1 Overview	13 Mechanical, Packaging, and Orderable
8.2 Functional Block Diagram 9	Information16

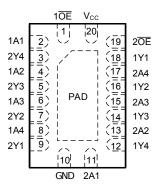
4 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

Changes from Revision * (July 2021) to Revision A (October 2021)	Page
• データシートを「事前情報」から「量産データ」に変更	0



5 Pin Configuration and Functions



RKS Package 20-Pin VQFN Top View

Pin Functions

PIN		I/O ⁽¹⁾	DESCRIPTION
NAME	NO.	1/0(1)	DESCRIPTION
1 OE	1	I	Bank 1, output enable, active low
1A1	2	I	Bank 1, channel 1 input
2Y4	3	0	Bank 2, channel 4 output
1A2	4	I	Bank 1, channel 2 input
2Y3	5	0	Bank 2, channel 3 output
1A3	6	I	Bank 1, channel 3 input
2Y2	7	0	Bank 2, channel 2 output
1A4	8	I	Bank 1, channel 4 input
2Y1	9	0	Bank 2, channel 1 output
GND	10	_	Ground
2A1	11	I	Bank 2, channel 1 input
1Y4	12	0	Bank 1, channel 4 output
2A2	13	I	Bank 2, channel 2 input
1Y3	14	0	Bank 1, channel 3 output
2A3	15	I	Bank 2, channel 3 input
1Y2	16	0	Bank 1, channel 2 output
2A4	17	I	Bank 2, channel 4 input
1Y1	18	0	Bank 1, channel 1 output
2 OE	19	I	Bank 2, output enable, active low
V _{CC}	20	_	Positive supply
Thermal Pad		_	The thermal pad can be connected to GND or left floating. Do not connect to any other signal or supply

(1) Signal Types: I = Input, O = Output, I/O = Input or Output.



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		-0.5	7	V
I _{IK}	Input clamp current ⁽²⁾ $V_1 < -0.5 \text{ V or } V_1 > V_{CC} + 0.5 \text{ V}$			±20	mA
I _{OK}	Output clamp current ⁽²⁾	$V_{O} < -0.5 \text{ V or } V_{O} > V_{CC} + 0.5 \text{ V}$		±20	mA
Io	Continuous output current	V _O = 0 to V _{CC}		±35	mA
I _{CC}	Continuous current through V _{CC} or GND			±70	mA
T_{J}	Junction temperature ⁽³⁾			150	°C
T _{stg}	Storage temperature		-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Rating may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Condition. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/ JEDEC JS-001 ⁽¹⁾	±4000	V
		Charged-device model (CDM), per ANSI/ESDA/ JEDEC JS-002 ⁽²⁾	±1500	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	2	5	6	V
VI	Input voltage	0		V _{CC}	V
Vo	Output voltage	0		V _{CC}	V
T _A	Ambient temperature	-55		125	°C

6.4 Thermal Information

		SN74HCS240	
	THERMAL METRIC ⁽¹⁾	RKS (VQFN)	UNIT
		20 PINS	-
R _{0JA}	Junction-to-ambient thermal resistance	83.2	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	82.6	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	57.4	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	14.5	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	56.4	°C/W

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⁽²⁾ The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

⁽³⁾ Guaranteed by design.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



		SN74HCS240		
	THERMAL METRIC(1)	RKS (VQFN)	UNIT	
		20 PINS		
R ₀ JC(bot)	Junction-to-case (bottom) thermal resistance	40.0	°C/W	

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

6.5 Electrical Characteristics

over operating free-air temperature range; typical values measured at T_A = 25°C (unless otherwise noted).

	PARAMETER	TEST CC	NDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
				2 V	0.7		1.5	
V_{T+}	Positive switching threshold			4.5 V	1.7		3.15	V
				6 V	2.1		4.2	
				2 V	0.3		1	
V_{T-}	Negative switching threshold			4.5 V	0.9		2.2	V
				6 V	1.2		3	
				2 V	0.2		1	
ΔV_{T}	Hysteresis (V _{T+} - V _{T-})			4.5 V	0.4		1.4	V
				6 V	0.6		1.6	
			I _{OH} = -20 μA	2 V to 6 V	V _{CC} - 0.1	V _{CC} - 0.002		
V_{OH}	High-level output voltage	$V_I = V_{IH}$ or V_{IL}	I _{OH} = -6 mA	4.5 V	4	4.3		V
			I _{OH} = -7.8 mA	6 V	5.4	5.75		
			I _{OL} = 20 μA	2 V to 6 V		0.002	0.1	
V_{OL}	Low-level output voltage	$V_I = V_{IH}$ or V_{IL}	I _{OL} = 6 mA	4.5 V		0.18	0.3	V
			I _{OL} = 7.8 mA	6 V		0.22	0.33	
I _I	Input leakage current	$V_I = V_{CC}$ or 0		6 V		±100	±1000	nA
l _{OZ}	Off-state (high-impedance state) output current	$V_{O} = V_{CC}$ or 0		6 V		±0.01	±2	μA
I _{CC}	Supply current	$V_I = V_{CC}$ or 0, I_C	_D = 0	6 V		0.1	2	μA
Ci	Input capacitance			2 V to 6 V			5	pF

6.6 Switching Characteristics

over operating free-air temperature range; typical values measured at T_A = 25°C (unless otherwise noted). See Parameter Measurement Information. C_L = 50 pF.

	PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC}	MIN	TYP	MAX	UNIT
				2 V		13	45	
t_{pd}	Propagation delay	Α	Υ	4.5 V		7	18	ns
				6 V		6	16	
				2 V		15	44	ns
t _{en}	Enable time	ŌĒ	Y	4.5 V		7	22	
				6 V		6	18	
		OE	Y	2 V		12	30	ns
t _{dis}	Disable time			4.5 V		9	20	
				6 V		8	19	
			Any	2 V		9	16	
t _t	Transition-time			4.5 V		5	9	ns
				6 V		4	8	



6.7 Operating Characteristics

over operating free-air temperature range; typical values measured at $T_A = 25$ °C (unless otherwise noted).

	0 1 0 7 71		<u>\</u>		
	PARAMETER	TEST CONDITIONS	MIN T	P MAX	UNIT
C _{pd}	Power dissipation capacitance per gar	te No load		20	pF

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6.8 Typical Characteristics

 $T_A = 25^{\circ}C$

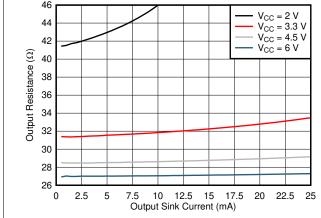


図 6-1. Output Driver Resistance in LOW State

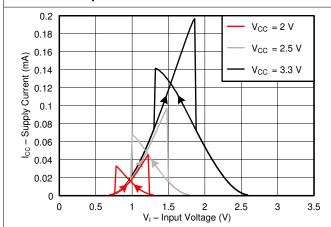


図 6-3. Supply Current Across Input Voltage, 2-, 2.5-, and 3.3-V Supply

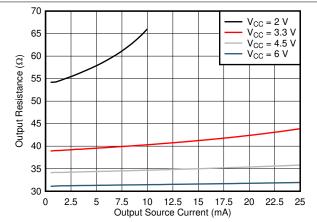


図 6-2. Output Driver Resistance in HIGH State

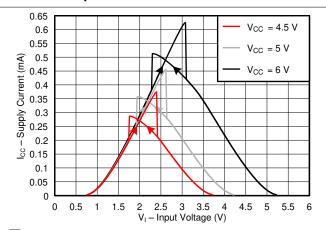


図 6-4. Supply Current Across Input Voltage, 4.5-, 5-, and 6-V Supply

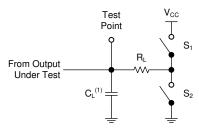


7 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_t < 2.5 ns.

For clock inputs, f_{max} is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.



(1) C_L includes probe and test-fixture capacitance.

図 7-1. Load Circuit for 3-State Outputs

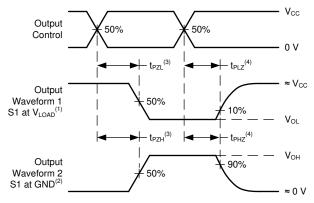
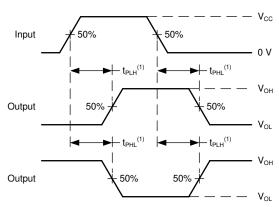
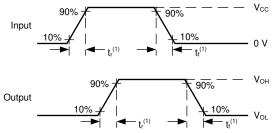


図 7-3. Voltage Waveforms Propagation Delays



(1) The greater between t_{PLH} and t_{PHL} is the same as t_{pd}.

図 7-2. Voltage Waveforms Propagation Delays



(1) The greater between t_r and t_f is the same as t_t.

図 7-4. Voltage Waveforms, Input and Output Transition Times

8 Detailed Description

8.1 Overview

The SN74HCS240 contains 8 individual high speed CMOS inverters with Schmitt-trigger inputs and 3-state outputs.

Each inverter performs the boolean logic function $xYn = \overline{xAn}$, with x being the bank number and n being the channel number.

Each output enable $(x\overline{OE})$ controls four inverters. When the $x\overline{OE}$ pin is in the low state, the outputs of all inverters in the bank x are enabled. When the $x\overline{OE}$ pin is in the high state, the outputs of all inverters in the bank x are disabled output are placed into the high-impedance state.

To ensure the high-impedance state during power up or power down, both \overline{OE} pins should be tied to V_{CC} through a pull-up resistor; the minimum value of the resistor is determined by the current sinking capability of the driver and the leakage of the pin as defined in the *Electrical Characteristics* table.

8.2 Functional Block Diagram

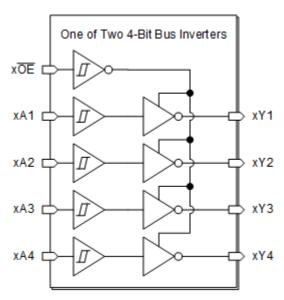


図 8-1. Logic Diagram (Positive Logic) for SN74HCS240

8.3 Feature Description

8.3.1 Balanced CMOS 3-State Outputs

This device includes balanced CMOS 3-State outputs. The three states that these outputs can be in are driving high, driving low, and high impedance. The term "balanced" indicates that the device can sink and source similar currents. The drive capability of this device may create fast edges into light loads so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. It is important for the output power of the device to be limited to avoid damage due to overcurrent. The electrical and thermal limits defined in the *Absolute Maximum Ratings* must be followed at all times.

When placed into the high-impedance mode, the output will neither source nor sink current, with the exception of minor leakage current as defined in the *Electrical Characteristics* table. In the high-impedance state, the output voltage is not controlled by the device and is dependent on external factors. If no other drivers are connected to the node, then this is known as a floating node and the voltage is unknown. A pull-up or pull-down resistor can be connected to the output to provide a known voltage at the output while it is in the high-impedance state. The value of the resistor will depend on multiple factors, including parasitic capacitance and power consumption limitations. Typically, a 10 k Ω resistor can be used to meet these requirements.

Unused 3-state CMOS outputs should be left disconnected.

8.3.2 CMOS Schmitt-Trigger Inputs

This device includes inputs with the Schmitt-trigger architecture. These inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in the *Electrical Characteristics* table from the input to ground. The worst case resistance is calculated with the maximum input voltage, given in the *Absolute Maximum Ratings* table, and the maximum input leakage current, given in the *Electrical Characteristics* table, using Ohm's law $(R = V \div I)$.

The Schmitt-trigger input architecture provides hysteresis as defined by ΔV_T in the *Electrical Characteristics* table, which makes this device extremely tolerant to slow or noisy inputs. While the inputs can be driven much slower than standard CMOS inputs, it is still recommended to properly terminate unused inputs. Driving the inputs with slow transitioning signals will increase dynamic current consumption of the device. For additional information regarding Schmitt-trigger inputs, please see Understanding Schmitt Triggers.

8.3.3 Clamp Diode Structure

The inputs and outputs to this device have both positive and negative clamping diodes as depicted in Electrical Placement of Clamping Diodes for Each Input and Output.

CAUTION

Voltages beyond the values specified in the *Absolute Maximum Ratings* table can cause damage to the device. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

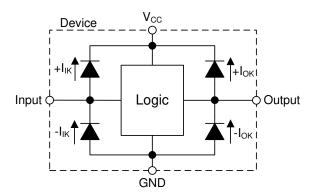


図 8-2. Electrical Placement of Clamping Diodes for Each Input and Output

8.4 Device Functional Modes

Function table lists the functional modes of the SN74HCS240.

表 8-1. Function Table

INPUTS ⁽¹⁾	OUTPUTS				
ŌĒ	A	Υ			
L	L	Н			
L	Н	L			
Н	X	Z			

(1) H = High Voltage Level, L = Low Voltage Level, X = Don't Care, Z = High-Impedance State

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9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

The SN74HCS240 can be used to drive signals over relatively long traces or transmission lines. In order to reduce ringing caused by impedance mismatches between the driver, transmission line, and receiver, a series damping resistor placed in series with the transmitter's output can be used. The plot in the *Application Curve* section shows the received signal with three separate resistor values. Just a small amount of resistance can make a significant impact on signal integrity in this type of application.

9.2 Typical Application

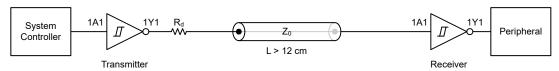


図 9-1. Typical application block diagram

9.2.1 Design Requirements

9.2.1.1 Power Considerations

Ensure the desired supply voltage is within the range specified in the *Recommended Operating Conditions*. The supply voltage sets the device's electrical characteristics as described in the *Electrical Characteristics*.

The positive voltage supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the SN74HCS240 plus the maximum static supply current, I_{CC} , listed in *Electrical Characteristics* and any transient current required for switching. The logic device can only source as much current as is provided by the positive supply source. Be sure not to exceed the maximum total current through V_{CC} listed in the *Absolute Maximum Ratings*.

The ground must be capable of sinking current equal to the total current to be sunk by all outputs of the SN74HCS240 plus the maximum supply current, I_{CC}, listed in *Electrical Characteristics*, and any transient current required for switching. The logic device can only sink as much current as can be sunk into its ground connection. Be sure not to exceed the maximum total current through GND listed in the *Absolute Maximum Ratings*.

The SN74HCS240 can drive a load with a total capacitance less than or equal to 50 pF while still meeting all of the data sheet specifications. Larger capacitive loads can be applied; however, it is not recommended to exceed 50 pF.



The SN74HCS240 can drive a load with total resistance described by $R_L \ge V_O$ / I_O , with the output voltage and current defined in the *Electrical Characteristics* table with V_{OH} and V_{OL} . When outputting in the high state, the output voltage in the equation is defined as the difference between the measured output voltage and the supply voltage at the V_{CC} pin.

Total power consumption can be calculated using the information provided in CMOS Power Consumption and Cpd Calculation.

Thermal increase can be calculated using the information provided in Thermal Characteristics of Standard Linear and Logic (SLL) Packages and Devices.

CAUTION

The maximum junction temperature, $T_{J(max)}$ listed in the *Absolute Maximum Ratings*, is an additional limitation to prevent damage to the device. Do not violate any values listed in the *Absolute Maximum Ratings*. These limits are provided to prevent damage to the device.

9.2.1.2 Input Considerations

Input signals must cross $V_{t-(min)}$ to be considered a logic LOW, and $V_{t+(max)}$ to be considered a logic HIGH. Do not exceed the maximum input voltage range found in the *Absolute Maximum Ratings*.

Unused inputs must be terminated to either V_{CC} or ground. These can be directly terminated if the input is completely unused, or they can be connected with a pull-up or pull-down resistor if the input is to be used sometimes, but not always. A pull-up resistor is used for a default state of HIGH, and a pull-down resistor is used for a default state of LOW. The resistor size is limited by drive current of the controller, leakage current into the SN74HCS240, as specified in the *Electrical Characteristics*, and the desired input transition rate. A 10-k Ω resistor value is often used due to these factors.

The SN74HCS240 has no input signal transition rate requirements because it has Schmitt-trigger inputs.

Another benefit to having Schmitt-trigger inputs is the ability to reject noise. Noise with a large enough amplitude can still cause issues. To know how much noise is too much, please refer to the $\Delta V_{T(min)}$ in the *Electrical Characteristics*. This hysteresis value will provide the peak-to-peak limit.

Unlike what happens with standard CMOS inputs, Schmitt-trigger inputs can be held at any valid value without causing huge increases in power consumption. The typical additional current caused by holding an input at a value other than V_{CC} or ground is plotted in the *Typical Characteristics*.

Refer to the Feature Description section for additional information regarding the inputs for this device.

9.2.1.3 Output Considerations

The positive supply voltage is used to produce the output HIGH voltage. Drawing current from the output will decrease the output voltage as specified by the V_{OH} specification in the *Electrical Characteristics*. The ground voltage is used to produce the output LOW voltage. Sinking current into the output will increase the output voltage as specified by the V_{OL} specification in the *Electrical Characteristics*.

Push-pull outputs that could be in opposite states, even for a very short time period, should never be connected directly together. This can cause excessive current and damage to the device.

Two channels within the same device with the same input signals can be connected in parallel for additional output drive strength.

Unused outputs can be left floating. Do not connect outputs directly to V_{CC} or ground.

Refer to Feature Description section for additional information regarding the outputs for this device.

9.2.2 Detailed Design Procedure

- Add a decoupling capacitor from V_{CC} to GND. The capacitor needs to be placed physically close to the
 device and electrically close to both the V_{CC} and GND pins. An example layout is shown in the Layout
 section.
- 2. Ensure the capacitive load at the output is ≤ 50 pF. This is not a hard limit, however it will ensure optimal performance. This can be accomplished by providing short, appropriately sized traces from the SN74HCS240 to one or more of the receiving devices.
- 3. Ensure the resistive load at the output is larger than $(V_{CC} / I_{O(max)}) \Omega$. This will ensure that the maximum output current from the *Absolute Maximum Ratings* is not violated. Most CMOS inputs have a resistive load measured in M Ω ; much larger than the minimum calculated above.
- 4. Thermal issues are rarely a concern for logic gates; the power consumption and thermal increase, however, can be calculated using the steps provided in the application report, CMOS Power Consumption and Cpd Calculation.

9.2.3 Application Curve

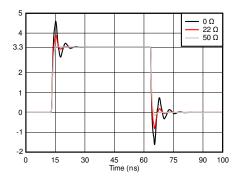


図 9-2. Simulated signal integrity at the reciever with different damping resistor (R_d) values

10 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- μ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results, as shown in given example layout image.

11 Layout

11.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC}, whichever makes more sense for the logic function or is more convenient.

11.2 Layout Example

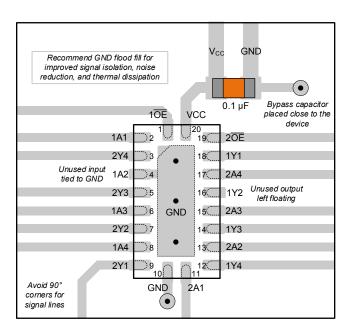


図 11-1. Example layout for the SN74HCS240 in the RKS Package

12 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

12.1 Documentation Support

12.1.1 Related Documentation

For related documentation see the following:

- Texas Instruments, HCMOS Design Considerations application report (SCLA007)
- Texas Instruments, CMOS Power Consumption and Cpd Calculation application report (SDYA009)
- · Texas Instruments, Designing With Logic application report

12.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.3 サポート・リソース

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12.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

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12.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.



13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

www.ti.com 10-Dec-2021

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
SN74HCS240RKSR	ACTIVE	VQFN	RKS	20	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCS240	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

www.ti.com 21-Oct-2021

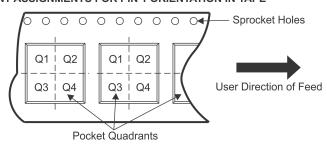
TAPE AND REEL INFORMATION





_		
		Dimension designed to accommodate the component width
	B0	Dimension designed to accommodate the component length
	K0	Dimension designed to accommodate the component thickness
	W	Overall width of the carrier tape
ı	P1	Pitch between successive cavity centers

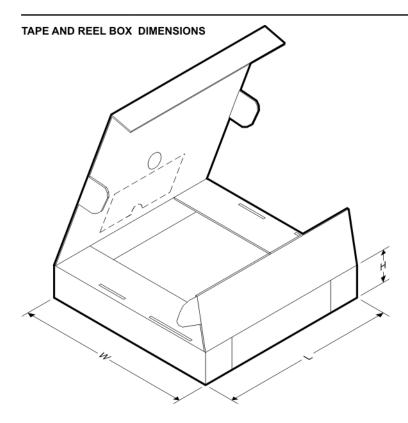
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing			Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74HCS240RKSR	VQFN	RKS	20	3000	180.0	12.4	2.8	4.8	1.2	4.0	12.0	Q1

www.ti.com 21-Oct-2021



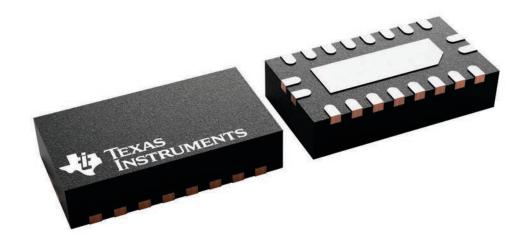
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Height (mm)	
SN74HCS240RKSR	VQFN	RKS	20	3000	210.0	185.0	35.0

2.5 x 4.5, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

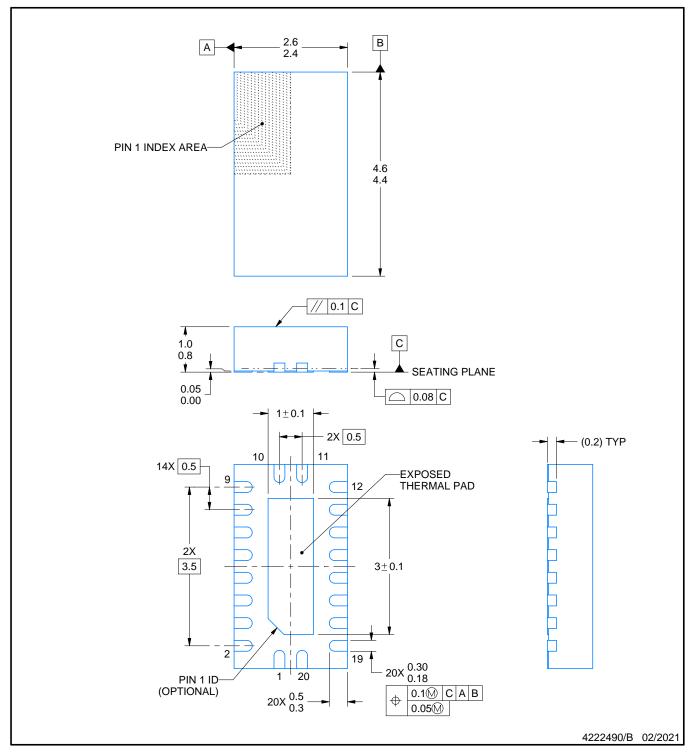
This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



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PLASTIC QUAD FLATPACK - NO LEAD

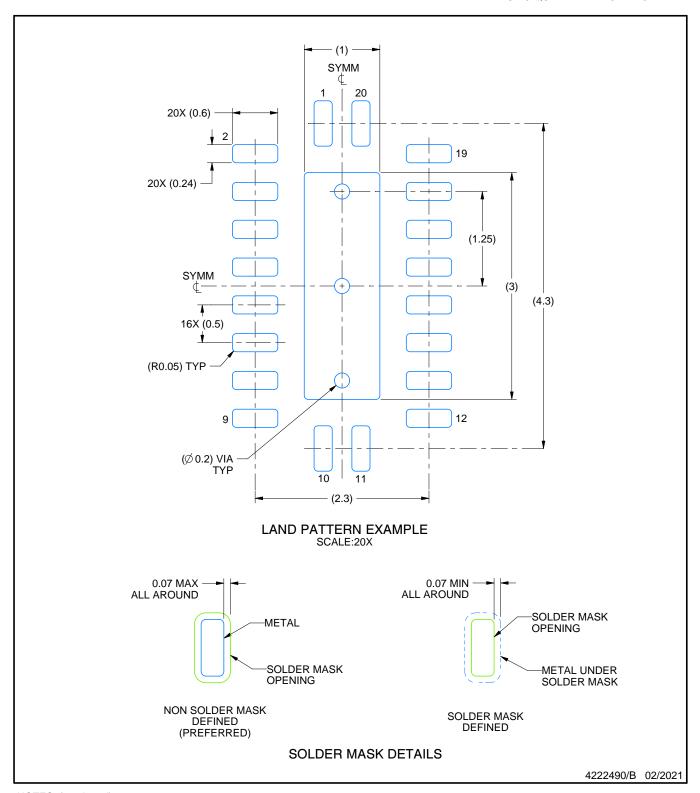


NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK - NO LEAD

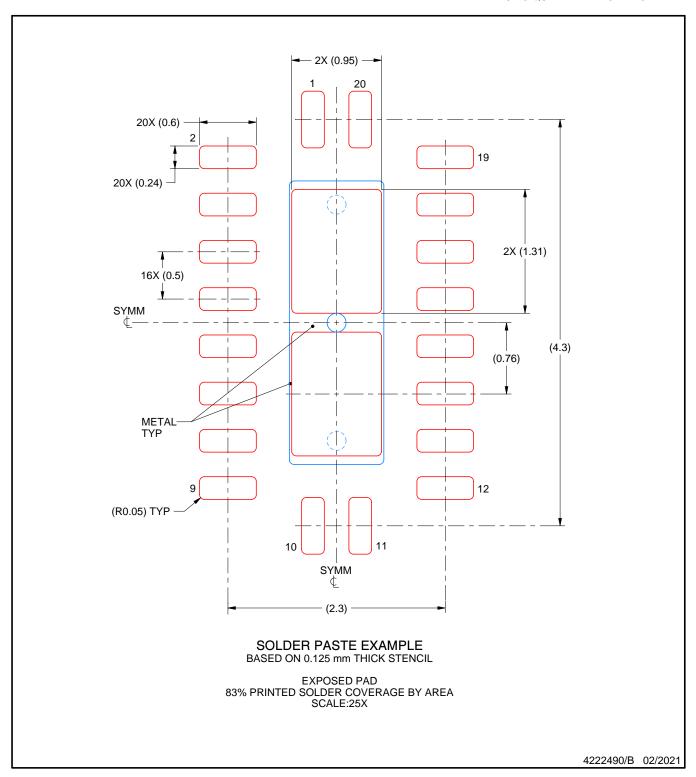


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If some or all are implemented, recommended via locations are shown.



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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